

REMARKS/ARGUMENTS

Claims 1-30 are pending. Claims 10, 23, and 27 have been amended. No new matter has been added.

Claims 10, 13, 23, and 26-28 were rejected under 35 U.S.C. § 102(e) as being anticipated by Nishikawa. Applicants respectfully traverse the rejection. Claim 10 is directed to a method for evaluating a color picture tube. The claim recites, among other features, "obtaining a first image by imaging said displayed measurement pattern with an imaging element under a first light intake condition of said imaging element; obtaining a second image by imaging said displayed measurement pattern with said imaging element under a second light intake condition of said imaging element..."

One of the features of the claimed invention relates to reducing loss of signal values. As explained in page 7 of the specification, the component with low signal values (i.e., darker components) are generally lost in noise and quantization errors. The above recited features are directed to measuring the minimum brightness in such a way to reduce such data loss. For example, a standard exposure image 701 is obtained by adjusting the light intake to prevent saturation at the maximum luminance value (page 7, lines 17-18). A long exposure image 702 of the same location is also obtained by extending exposure time to prevent the minimum brightness from being lost in noise (page 7, lines 18-20). These two images that are obtained using two different light intake conditions are combined to prevent losing lower signal values to the noise, quantization errors, or the like.

Nishikawa discloses an apparatus for measuring a profile of an electron beam of a CRT. The Examiner stated that the above features are disclosed in Fig. 8 and at col. 9:4 to col. 10:44. Applicants respectfully disagree.

Nishikawa discloses obtaining a plurality of images of a test pattern that is displayed on a screen by changing raster size. Nishikawa does not describe using different light intake conditions to obtain different images of a displayed pattern. That is, Nishikawa does not disclose "obtaining a first image by imaging said displayed measurement pattern with an imaging element under a first light intake condition of said imaging element; obtaining a second image by

imaging said displayed measurement pattern with said imaging element under a second light intake condition of said imaging element..." Claim 10 is allowable at least for the above reason.

Claim 23 recites, "imaging means for obtaining a first image and a second image by imaging said displayed measurement pattern under a first light intake condition and a second light intake condition, the first image being obtained with an imaging element under said first light intake condition of said imaging element, the second image being obtained with said imaging element under said second light intake condition of said imaging element..." Nishikawa does not disclose the above recited feature. Claim 23 is allowable at least for the reason set forth above.

Claim 27 recites, "obtaining a first image by imaging said displayed measurement pattern with an imaging element under a first light intake condition of said imaging element, obtaining a second image by imaging said displayed measurement pattern with said imaging element under a second light intake condition of said imaging element..." Nishikawa does not disclose the above recited features. Claim 27 is allowable at least for this reason.

Other claims depend from one of the above claims and are allowable at least for this reason.

Claims 12 and 25 were rejected under 35 U.S.C. § 103(a) as being unpatentable over Nishikawa. Applicants respectfully traverse the rejection. Claims 12 and 25 depend from claims 10 and 23, respectively, and are allowable at least for the reasons claims 10 and 23 are allowable.

Applicants thank the Examiner for indicating that claim 1-9, 14-22, and 29-30 and that claims 11 and 24 included allowable subject matters

CONCLUSION

In view of the foregoing, Applicants believe all claims now pending in this Application are in condition for allowance. The issuance of a formal Notice of Allowance at an early date is respectfully requested.

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PATENT

If the Examiner believes a telephone conference would expedite prosecution of this application, please telephone the undersigned at .

Respectfully submitted,



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